

Search Notes

Application No.

09/754,155

Examiner

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Applicant(s)

WEIL ET AL.

Art Unit

2162

SEARCHED

Class	Subclass	Date	Examiner
707	3	2/9/2005	CC
707	2	2/9/2005	CC
707	9	2/9/2005	CC
707	10	2/9/2005	CC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
707	2,3,9,10	2/9/2005	CC

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PALM	2/9/2005	CC
EAST search (USPAT, US-PGPUB, IBM_TDB)	2/9/2005	CC
EIC search	2/9/2005	CC
None Patent Literature Search (Google, IEEE, ACM)	2/9/2005	CC
Consulted with Jean Corrielus	2/9/2005	CC